PATENT 2185-0578P



IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant:	Yoshinobu ONO et al.	Conf.:	3053	TEC	
Appl. No.:	09/977,375	Group:	2811	JUH ?	RECE
Filed:	October 16, 2001	Examiner:	Junghw	2 9	MEI
For:	3-5 GROUP COMPOUND SEMICOLLIGHT-EMITTING ELEMENT	ONDUCTOR AL	ND	TER 2805	

LARGE ENTITY TRANSMITTAL FORM

Assistant Commissioner for Patents Washington, DC 20231

June 20, 2002

Sir:

Transmitted	he	erew	ith	is	a	Reply	to	Restriction/	Election
Requirement									

	smitted herewith is a Reply to Restriction/Election irement in the above-identified application.
	The enclosed document is being transmitted via the Certificate of Mailing provisions of 37 C.F.R. § 1.8.
	Petition for () month(s) extension of time pursuant to 37 C.F.R. §§ 1.17 and 1.136(a). \$0.00 for the extension of time.
\boxtimes	No fee is required.
	A check in the amount of \$0.00 is enclosed.
	Please charge Deposit Account No. 02-2448 in the amount of \$0.00. A triplicate copy of this sheet is attached.

Appl. No. 09/977,375

If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies, to charge payment or credit any overpayment to Deposit Account No. 02-2448 for any additional fees required under 37 C.F.R. §§1.16 or 1.17; particularly, extension of time fees.

Respectfully submitted,

BIRCH, STEWART, KOLASCH & BIRCH, LLP

Ву_

ADM/REG

2185-0578P

Andrew D. Meikle, #32,868

P.O. Box 747

Falls Church, VA 22040-0747

(703) 205-8000

(Rev. 09/27/01)



PATENT 2185-0578P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant:

Yoshinobu ONO et al.

Conf.:

3053

Appl. No.:

09/977,375

Group:

2811

Filed:

October 16, 2001

Examiner: Junghwa

For:

3-5 GROUP COMPOUND SEMICONDUCTOR AND

LIGHT-EMITTING ELEMENT

REPLY TO RESTRICTION REQUIREMENT

Assistant Commissioner for Patents Washington, DC 20231

June 20, 2002

Sir:

In reply to the Restriction Requirement dated May 21, 2002, the following remarks are respectfully submitted in connection with the above-identified application.

REMARKS

Claims 1-13 are pending in the present application.

The Examiner has required election in the present application between:

Group I, claims 1-11, drawn to a semiconductor device; and Group II, claims 12-13, drawn to a method of measuring dislocation density.

For the purpose of examination of the present application,
Applicants elect, without traverse, Group I, claims 1-11.